

# STD50NH02L STD50NH02L-1

## N-channel 24V - 0.0085Ω - 50A - DPAK/IPAK STripFET™ III Power MOSFET

### **General features**

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub>	Ι <sub>D</sub>
STD50NH02L-1	24V	<0.0105Ω	50A
STD50NH02L	24V	<0.0105Ω	50A

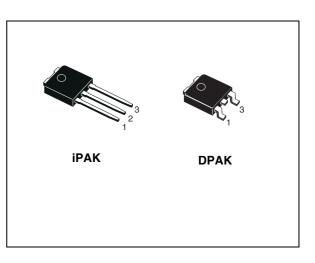
- Logic level device
- R<sub>DS(ON)</sub> \* Q<sub>g</sub> Industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold drive

## Description

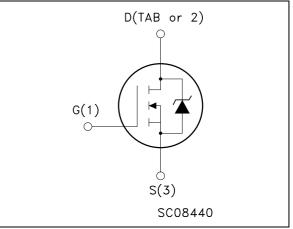
This device utilizes the latest advanced design rules of ST's proprietary STripFET<sup>™</sup> technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

## Applications

Switching application



## Internal schematic diagram



### Order codes

Part number	Marking	Package	Packaging
STD50NH02L-1	D50NH02L	IPAK	Tube
STD50NH02LT4	D50NH02L	DPAK	Tape & reel

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# 1 Electrical ratings

Table 1. Absolute maximum rating
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Symbol	Parameter	Value	Unit
V <sub>spike</sub> <sup>(1)</sup>	Drain-source voltage rating	30	V
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	24	V
V <sub>DGR</sub>	Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)	24	V
V <sub>GS</sub>	Gate- source voltage	± 20	V
I <sub>D</sub>	Drain current (continuous) at $T_C = 25^{\circ}C$	50	A
۱ <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100°C	36	A
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	200	А
P <sub>tot</sub>	Total dissipation at $T_{C} = 25^{\circ}C$	on at $T_C = 25^{\circ}C$ 60 V	
	Derating Factor	Derating Factor 0.4 V	
E <sub>AS</sub> <sup>(3)</sup>	Single pulse avalanche energy	ingle pulse avalanche energy 280 m	
T <sub>stg</sub>	Storage temperature		°C
Тj	Max. operating junction temperature	55 to 175	C C

1. Garanted when external R<sub>g</sub>=4.7  $\Omega$  and t<sub>f</sub> < t<sub>fmax</sub>.

2. Pulse width limited by safe operating area.

3. Starting  $T_j = 25 \text{ °C}$ ,  $I_D = 19A$ ,  $V_{DD} = 18V$ 

	Table	2.	Thermal	data
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Rthj-case	Thermal resistance junction-case max	2.5	°C/W
Rthj-amb Thermal resistance junction-ambient max		100	°C/W
TJ	Maximum lead temperature for soldering purpose	275	°C

# 2 Electrical characteristics

(T<sub>CASE</sub>=25°C unless otherwise specified)

Symbol	Parameter Test conditions Min.		Тур.	Max.	Unit	
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 25mA, V <sub>GS</sub> =0	24			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	$V_{DS} = 20V$ $V_{DS} = 20V$ , $T_{C} = 125^{\circ}C$			1 10	μΑ μΑ
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 20V$			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.8		V
R <sub>DS(on)</sub>	Static drain-source on resistance	$V_{GS} = 10V, I_D = 25A$ $V_{GS} = 5V, I_D = 12.5A$		0.0085 0.012	0.0105 0.020	Ω Ω

#### Table 3. On/off states

#### Table 4. Dynamic

	Dynamic					
Symbol	Parameter Test conditions Min.		Тур.	Max.	Unit	
g <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	V <sub>DS</sub> = 15V <sub>,</sub> I <sub>D</sub> = 25A		27		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> = 25V, f = 1MHz, V <sub>GS</sub> = 0		1400 400 55		pF pF pF
R <sub>G</sub>	Gate Input Resistance	f = 1 MHz Gate DC Bias = 0 Test Signal Level = 20 mV Open Drain		1		Ω
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 10V, I_D = 25A$ $R_G = 4.7\Omega V_{GS} = 10V$ (see <i>Figure 13</i> )		10 130 27 16		ns ns ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$\label{eq:VDD} \begin{split} V_{DD} &= 10 V, \ I_D = 50 A, \\ V_{GS} &= 10 V, \ R_G = 4.7 \Omega \\ (see \ Figure \ 14) \end{split}$		24 5 3.5		nC nC nC
Q <sub>oss</sub> <sup>(2)</sup>	Output charge	$V_{DS}$ = 16 V, $V_{GS}$ = 0 V		9.5		nC

1. Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %.

2. Qoss = Coss<sup>\*</sup> $\Delta$  Vin , Coss = Cgd + Cds . See *Chapter 4: Appendix A* 



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current Source-drain current (pulsed)				50 200	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 25A, V <sub>GS</sub> = 0			1.3	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 50A, di/dt = 100A/\mu s,$ $V_{DD} = 20V, T_j = 150^{\circ}C$ (see <i>Figure 15</i> )		36 36 2		ns nC A

Table 5.Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %



GC99670

Vos=25V

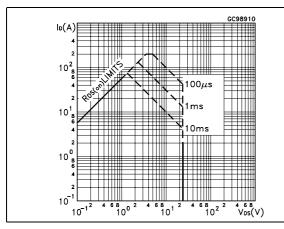
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 $V_{GS}(V)$ 

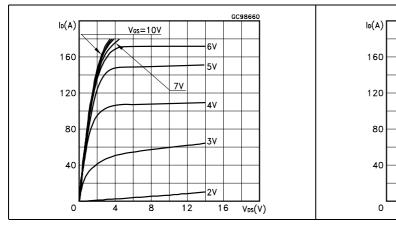
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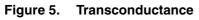
### 2.1 Electrical characteristics (curves)

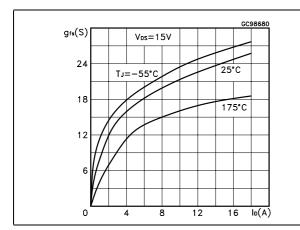
### Figure 1. Safe operating area













4

6

2

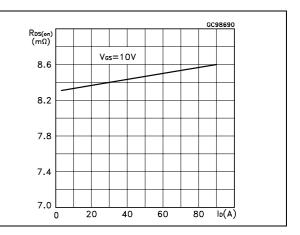
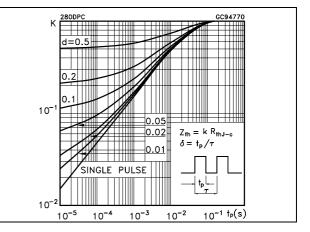


Figure 4. Transfer characteristics

Figure 2.



**Thermal impedance** 

### Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

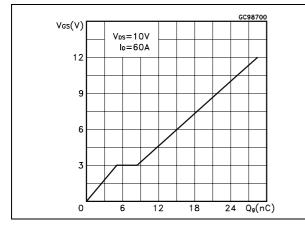


Figure 9. Normalized gate threshold voltage vs temperature

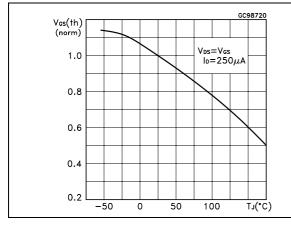


Figure 11. Source-drain diode forward characteristics

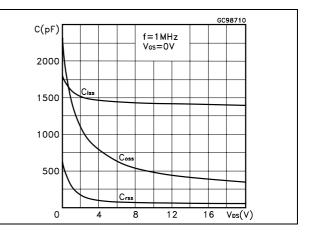


Figure 10. Normalized on resistance vs temperature

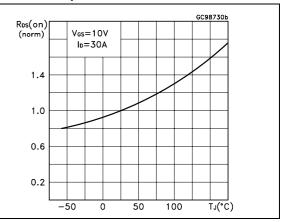
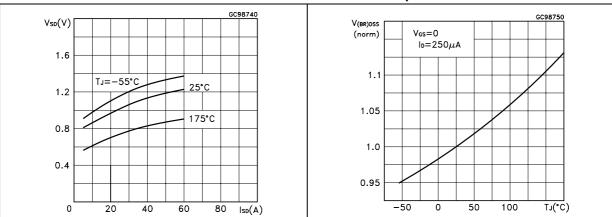


Figure 12. Normalized breakdown voltage vs temperature



## 3 Test circuit

Figure 13. Switching times test circuit for resistive load

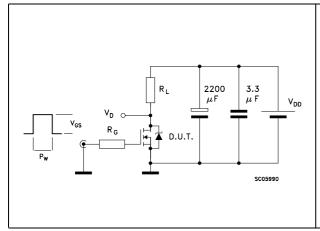
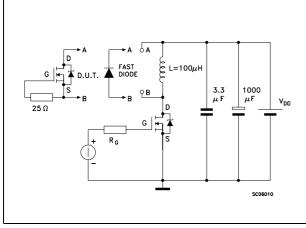


Figure 15. Test circuit for inductive load switching and diode recovery times





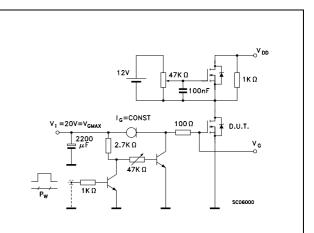
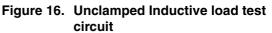


Figure 14. Gate charge test circuit



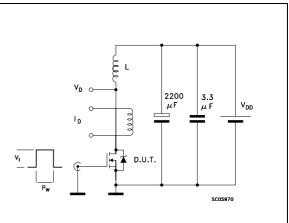
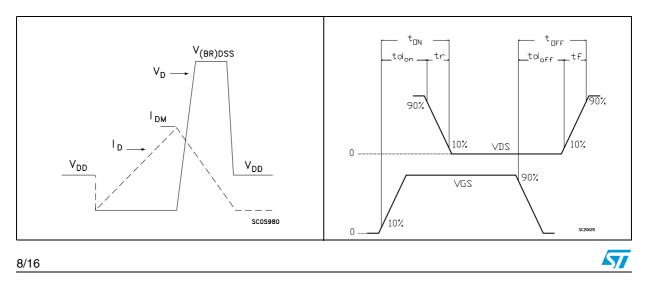
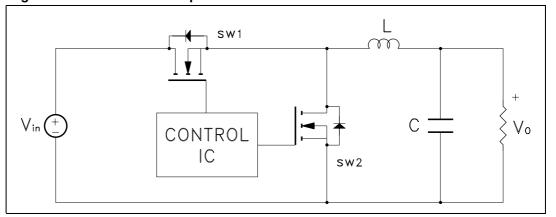


Figure 18. Switching time waveform



### 4 Appendix A





The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R<sub>DS(on)</sub> to reduce conduction losses
- Small Qgls to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R<sub>DS(on)</sub> to reduce the conduction losses.



		High side switching (SW1)	Low side switch (SW2)
Pconduction		$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
Pswitching		$V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
Pdiode	Recovery (1)	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
Fulde	Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
Pgate(Q <sub>G</sub> )		$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$
P <sub>Qoss</sub>		$\frac{V_{in} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$

 Table 6.
 Power losses calculation

1. Dissipated by SW1 during turn-on

Table 7. Paramiters meaning	ng
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Parameter	Meaning			
d	Duty-cycle			
Q <sub>gsth</sub>	Post threshold gate charge			
Q <sub>gls</sub>	Third quadrant gate charge			
Pconduction	On state losses			
Pswitching	On-off transition losses			
Pdiode	Conduction and reverse recovery diode losses			
Pgate	Gate drive losses			
P <sub>Qoss</sub>	Output capacitance losses			



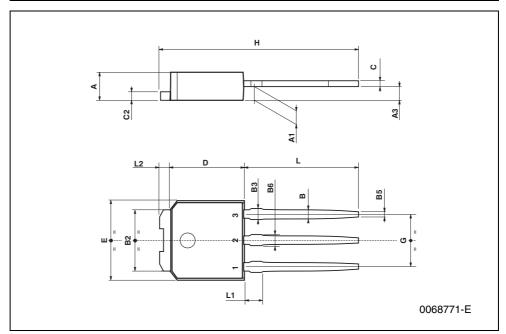
## 5 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



DIM.	mm			inch		
DINI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039

### TO-251 (IPAK) MECHANICAL DATA



DIM	mm.			inch		
DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°
		SEATING PLANE	e e	<u> </u>		

V2 0,25 GAUGE PLANE

### 

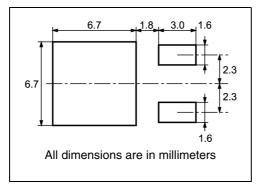


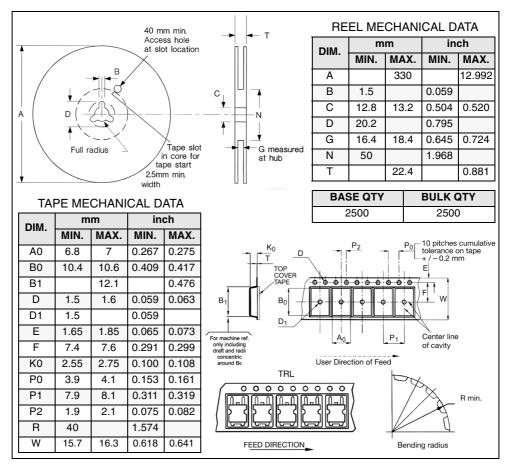
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## 6 Packing mechanical data

### **DPAK FOOTPRINT**





#### TAPE AND REEL SHIPMENT

# 7 Revision history

Table 8.	Revision	history
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Date	Revision	Changes
21-Jun-2004	6	Preliminary version
11-Jul-2006	7	New template, no content change



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